## **TOSHIBA**

TOSHIBA Field Effect Transistor Silicon N Channel MOS Type ( $\pi$ -MOSIII)

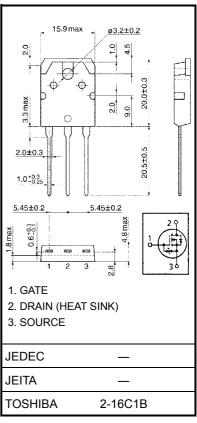
# 2SK2968

## DC–DC Converter, Relay Drive and Motor Drive Applications

- Low drain-source ON resistance  $: R_{DS} (ON) = 1.05 \Omega (typ.)$
- High forward transfer admittance  $|Y_{fs}| = 7.6 \text{ S (typ.)}$
- Low leakage current  $: I_{DSS} = 100 \ \mu A \ (max) \ (V_{DS} = 720 \ V)$
- Enhancement-mode  $: V_{th} = 2.0 \sim 4.0 \text{ V} (V_{DS} = 10 \text{ V}, \text{I}_{D} = 1 \text{ mA})$

#### Maximum Ratings (Ta = 25°C)

Characteris	stics	Symbol	Rating	Unit	
Drain-source voltage		V <sub>DSS</sub>	900	V	
Drain-gate voltage (R	<sub>GS</sub> = 20 kΩ)	V <sub>DGR</sub>	900	V	
Gate-source voltage		V <sub>GSS</sub>	±30	V	
Drain current	DC (Note 1)	I <sub>D</sub>	10	А	
	Pulse (Note 1)	I <sub>DP</sub>	30	А	
Drain power dissipation	n (Tc = 25°C)	PD	150	W	
Single pulse avalanche	e energy (Note 2)	E <sub>AS</sub>	810	mJ	
Avalanche current		I <sub>AR</sub>	10	А	
Repetitive avalanche e	nergy (Note 3)	E <sub>AR</sub>	15	mJ	
Channel temperature		T <sub>ch</sub>	150	°C	
Storage temperature ra	ange	T <sub>stg</sub>	-55~150	°C	



Weight: 4.6 g (typ.)

#### **Thermal Characteristics**

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R <sub>th (ch−c)</sub>	0.833	°C / W
Thermal resistance, channel to ambient	R <sub>th (ch−a)</sub>	50	°C / W

Note 1: Please use devices on condition that the channel temperature is below 150°C.

Note 2:  $V_{DD}$  = 90 V,  $T_{ch}$  = 25°C (initial), L = 14.9 mH,  $R_G$  = 25  $\Omega$ ,  $I_{AR}$  = 10 A

Note 3: Repetitive rating: Pulse width limited by maximum channel temperature

This transistor is an electrostatic sensitive device. Please handle with caution.

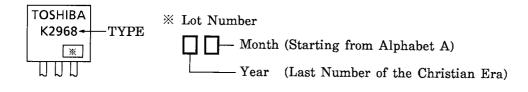
Electrical Characteristics (Ta = 25°C)

Charac	teristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cu	irrent	I <sub>GSS</sub>	V <sub>GS</sub> = ±30 V, V <sub>DS</sub> = 0 V		_	±10	μA
Gate-source bre	eakdown voltage	V (BR) GSS	$I_{G}$ = ±10 µA, $V_{DS}$ = 0 V	±30		_	V
Drain cut-off cu	rrent	I <sub>DSS</sub>	V <sub>DS</sub> = 720 V, V <sub>GS</sub> = 0 V	_	-	100	μA
Drain-source br	eakdown voltage	V (BR) DSS	I <sub>D</sub> = 10 mA, V <sub>GS</sub> = 0 V	900	_	_	V
Gate threshold v	voltage	V <sub>th</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 1 mA	2.0	_	4.0	V
Drain-source O	N resistance	R <sub>DS (ON)</sub>	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 4 A	_	1.05	1.25	Ω
Forward transfer	r admittance	Y <sub>fs</sub>	V <sub>DS</sub> = 15 V, I <sub>D</sub> = 4 A	3.5	7.6	_	S
Input capacitance	e	C <sub>iss</sub>		_	2150	_	
Reverse transfer capacitance		C <sub>rss</sub>	V <sub>DS</sub> = 25 V, V <sub>GS</sub> = 0 V, f = 1 MHz	_	35	_	pF
Output capacitance		C <sub>oss</sub>			220	_	
Switching time	Rise time	tr	$V_{GS} \stackrel{10V}{}_{0V} \int I_{D} = 5A$ $V_{UT} \stackrel{V_{UT}}{}_{RL} = 80\Omega$ $V_{DD} = 400V$	_	25	-	- ns
	Turn-on time	t <sub>on</sub>		_	60	_	
	Fall time	t <sub>f</sub>		_	25	_	
	Turn-off time	t <sub>off</sub>	Duty $\leq 1\%$ , t <sub>w</sub> =10 $\mu$ s	_	120	_	
Total gate charge (gate-source plus gate-drain)		Qg		_	70	_	
Gate-source charge		Q <sub>gs</sub>	V <sub>DD</sub> ≈ 400 V, V <sub>GS</sub> = 10 V, I <sub>D</sub> = 10 A		37	_	nC
Gate-drain ("miller") Charge		Q <sub>gd</sub>			33	—	

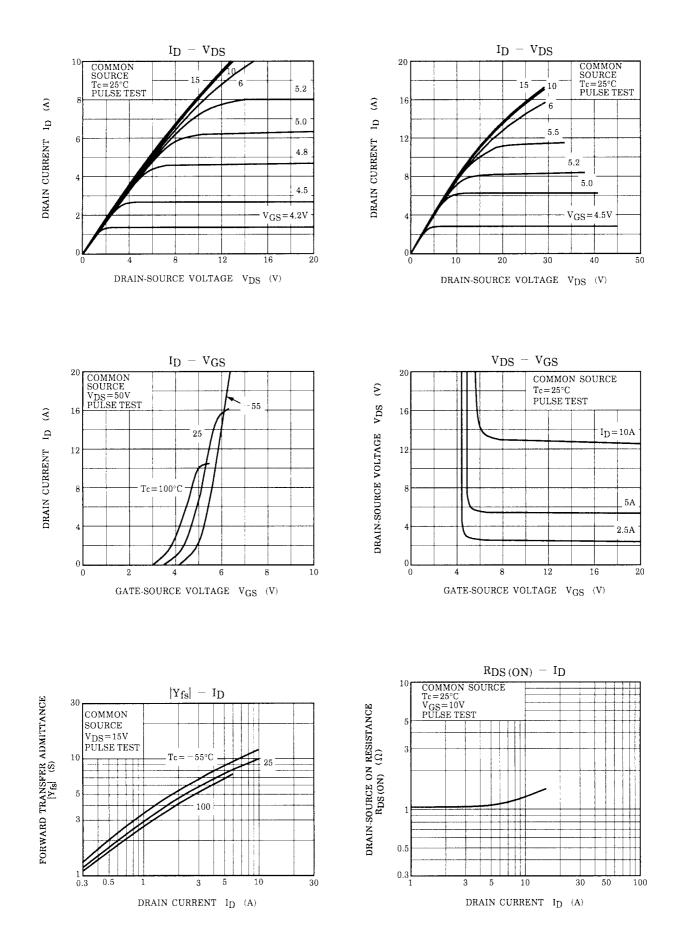
#### Source–Drain Ratings and Characteristics (Ta = 25°C)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I <sub>DR</sub>	—	_	_	10	А
Pulse drain reverse current (Note 1)	I <sub>DRP</sub>	_	_	_	30	А
Forward voltage (diode)	V <sub>DSF</sub>	I <sub>DR</sub> = 10 A, V <sub>GS</sub> = 0 V	_	—	-1.9	V
Reverse recovery time	t <sub>rr</sub>	I <sub>DR</sub> = 10 A, V <sub>GS</sub> = 0 V dI <sub>DR</sub> / dt = 100 A / μs		1300		ns
Reverse recovery charge	Q <sub>rr</sub>	dI <sub>DR</sub> / dt = 100 A / μs	_	14.5	_	μC

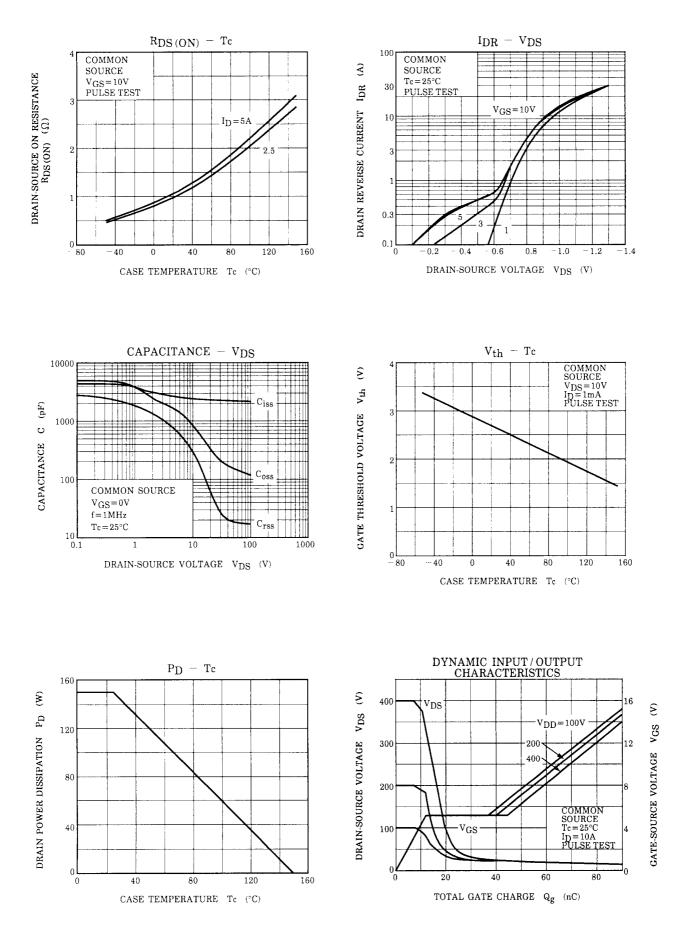
#### Marking

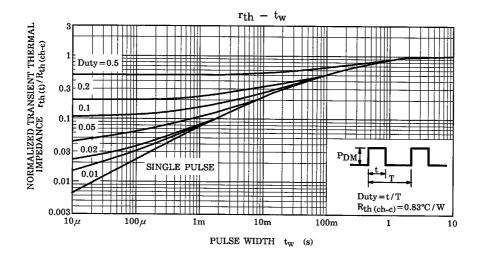


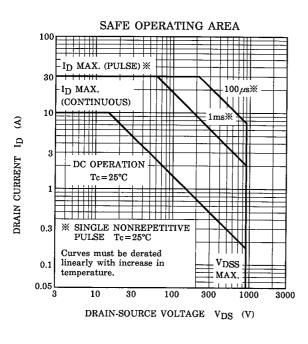
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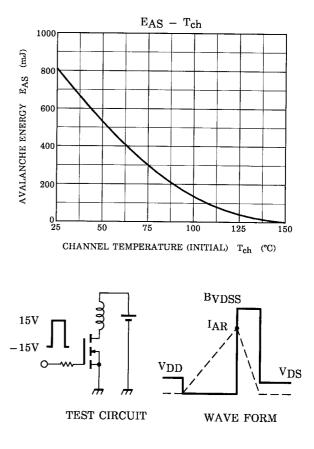


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